

**Search Notes**

Application/Control No.

09/754,441

Examiner

Hai V. Nguyen

Applicant(s)/Patent under  
Reexamination

YOSHIHARA ET AL.

Art Unit

2142

**SEARCHED**

Class	Subclass	Date	Examiner
709	245	5/22/2006	HN
84	622	5/22/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search Updated (USPGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history report printout)	5/22/2006	HN
Limited Classified Search (709/245' 84/622) (ee search history report printout)	5/22/2006	HN